

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of Sherrer

Application No. 10/790,339

Attorney Docket No.: R&H 04-02; DN 51910 (ACT - 115)

Filed: March 1, 2004

For: MICROSTRUCTURES COMPRISING A

DIELECTRIC LAYER AND A THIN

CONDUCTIVE LAYER

CERTIFICATE OF MAILING UNDER 37 C.F.R § 1.8(a)

I hereby certify that this Correspondence is being deposited on the date identified below with the United States Postal Service as first-class mail in an envelope properly addressed to Commissioner for Patents, Alexandria, VA 22313-1450

May 27, 2004

Date of Certificate

Cristin Donahue

Commissioner for Patents Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97

In compliance with the duty of disclosure set forth in 37 C.F.R. § 1.56, Applicants are submitting herewith a Form PTO-1449 and a copy of the references listed thereon. This Information Disclosure Statement is being filed within three months of the filing date. Accordingly no fee is required.

Applicants respectfully request full and proper consideration of the listed information during examination of the application, and that the listed information be printed on any patent that issues therefrom.

Respectfully submitted,

DANN, DORFMAN, HERRELL & SKILLMAN

A Professional Corporation Attorneys for Applicant(s)

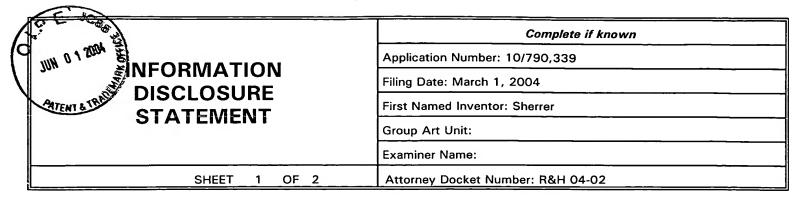
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Niels Haury

PTO Registration No. 48,488

Telephone: (215) 563-4100 Facsimile: (215) 563-4044 Enclosures - Form PTO-1449

Copies of references listed on PTO - 1449



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EXAMINER'S	DATE	
SIGNATURE	CONSIDERED	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609. Draw a line through citation if citation not in conformance and reference not considered. Include a copy of this form with next communication to applicant.

INFORMATION DISCLOSURE STATEMENT

SHEET

OF 2

Complete if known	
Application Number: 10/790,339	
Filing Date: March 1, 2004	
First Named Inventor: Sherrer	
Group Art Unit:	
Examiner Name:	
Attorney Docket Number: R&H 04-02	

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FOREIGN PATENT DOCUMENTS					
EXAMINER'S INITIALS	CITE NO.	DOCUMENT NUMBER	COUNTRY OR REGION	DATE OF PUBLICATION MM-DD-YYYY	FIRST NAMED INVENTOR OR APPLICANT

OTHER PRIOR ART - NON-PATENT DOCUMENTS				
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in Capital Letters), title of the article (when appropriate), title of the item(book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published		

			
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